

CLAIMS

What is claimed is:

1. A probe module comprising:  
a probe base;  
a plurality of probe pins carried by said probe base; and  
a circuit interconnect device for connecting said plurality of probe pins to an inspection apparatus.
2. The probe module of claim 1 wherein each of said plurality of probe pins comprises a probe pin body, a probe pin head carried by said probe pin body and a generally tapered probe pin tip provided on said probe pin head.
3. The probe module of claim 1 wherein said circuit interconnect device comprises a plurality of conductive probe circuits provided on said probe base in electrical contact with said plurality of probe pins, respectively, and a flexible circuit board provided in electrical contact with said plurality of conductive probe circuits.

4. The probe module of claim 3 wherein each of said plurality of probe pins comprises a probe pin body, a probe pin head carried by said probe pin body and a generally tapered probe pin tip provided on said probe pin head.

5. The probe module of claim 1 wherein each of said plurality of probe pins comprises a probe pin body, a probe pin head carried by said probe pin body and a generally semi-spherical probe pin tip provided on said probe pin head.

6. The probe module of claim 5 wherein said circuit interconnect device comprises a plurality of conductive probe circuits provided on said probe base in electrical contact with said plurality of probe pins, respectively, and a flexible circuit board provided in electrical contact with said plurality of conductive probe circuits.

7. The probe module of claim 1 further comprising a compression arm carried by said probe base and engaging said plurality of probe pins.

8. The probe module of claim 7 wherein each of said plurality of probe pins comprises a probe pin body, a probe pin head carried by said probe pin body and a generally tapered probe pin tip provided on said probe pin head.

9. The probe module of claim 7 wherein said circuit interconnect device comprises a plurality of conductive probe circuits provided on said probe base in electrical contact with said plurality of probe pins, respectively, and a flexible circuit board provided in electrical contact with said plurality of conductive probe circuits.

10. The probe module of claim 9 wherein each of said plurality of probe pins comprises a probe pin body, a probe pin head carried by said probe pin body and a generally tapered probe pin tip provided on said probe pin head.

11. The probe module of claim 7 wherein each of said plurality of probe pins comprises a probe pin body, a probe pin head carried by said probe pin body and a generally semi-spherical probe pin tip provided on said probe pin head.

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12. The probe module of claim 11 wherein said circuit interconnect device comprises a plurality of conductive probe circuits provided on said probe base in electrical contact with said plurality of probe pins, respectively, and a flexible circuit board provided in electrical contact with said plurality of conductive probe circuits.

13. A probe module comprising:  
a probe base;  
a plurality of probe pins each having a generally tetrahedral probe pin tip carried by said probe base; and  
a circuit interconnect device for connecting said plurality of probe pins to an inspection apparatus.

14. The probe module of claim 13 wherein each of said plurality of probe pins comprises a probe pin body and a probe pin head carried by said probe pin body, and wherein said probe pin tip is provided on said probe pin head.

15. The probe module of claim 13 wherein said circuit interconnect device comprises a plurality of conductive probe circuits provided on said probe base in electrical contact with said plurality of probe pins, respectively, and a flexible circuit board provided in electrical contact with said plurality of conductive probe circuits.

16. The probe module of claim 15 wherein each of said plurality of probe pins comprises a probe pin body and a probe pin head carried by said probe pin body, and wherein said probe pin tip is provided on said probe pin head.

17. The probe module of claim 13 further comprising a compression arm carried by said probe base and engaging said plurality of probe pins.

18. A probe pin for a probe module, comprising:  
a probe pin body;  
a probe pin head carried by said probe pin body; and  
a probe pin tip provided on said probe pin head.

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19. The probe pin of claim 17 wherein said probe pin tip has a generally polyhedral configuration.

20. The probe pin of claim 17 wherein said probe pin tip has a generally semi-spherical configuration.